

Notice of References Cited	Application/Control No. 10/568,159	Applicant(s)/Patent Under Reexamination CAPUTO, GIUSEPPE	
	Examiner Yong Chu	Art Unit 1626	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0225247	12-2003	Stavrianopoulos et al.	530/350
*	B	US-2002/0065421	05-2002	Caputo et al.	548/427
*	C	US-2002/0051926	05-2002	Takashima et al.	430/138
*	D	US-6,136,612	10-2000	Della Ciana et al.	436/546
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Page 1 of 1

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